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Isolated Compact IGBT **Gate Driver with DESAT**

NCD57084, NCV57084

NCx57084 is a high current single channel IGBT gate driver with 2.5 kVrms internal galvanic isolation designed for high system efficiency and reliability in high power applications. The driver includes DESAT short circuit protection with soft turn off and fault reporting in a narrow body SOIC-8 package. NCx57084 accommodates wide range of input bias voltage and signal levels from 3.3 V to 20 V, and wide range of output bias voltage up to 30 V.

Features

- High Peak Output Current (+7A/-7 A)
- Low Output Impedance for Enhanced IGBT Driving
- Short Propagation Delays with Accurate Matching
- DESAT Protection with Programmable Delay
- Negative Voltage (Down to -9 V) Capability for DESAT
- IGBT Gate Clamping during Short Circuit
- IGBT Gate Active Pull Down
- Soft Turn Off During IGBT Short Circuit
- Tight UVLO Thresholds for Bias Flexibility
- Output Partial Pulse Avoidance During UVLO/DESAT (Restart)
- 3.3 V, 5 V, and 15 V Logic Input
- 2.5 kVrms Galvanic Isolation
- High Transient Immunity
- High Electromagnetic Immunity
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- This Device is Pb-Free, Halogen Free/BFR Free and is RoHS Compliant

Typical Applications

- Motor Control
- Automotive Applications
- Uninterruptible Power Supplies (UPS)
- Industrial Power Supplies
- HVAC
- Industrial Pumps and Fans



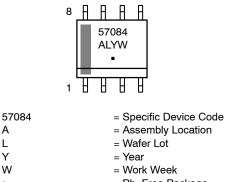
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MARKING DIAGRAM



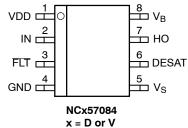
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ORDERING INFORMATION

See detailed ordering and shipping information on page 10 of this data sheet.

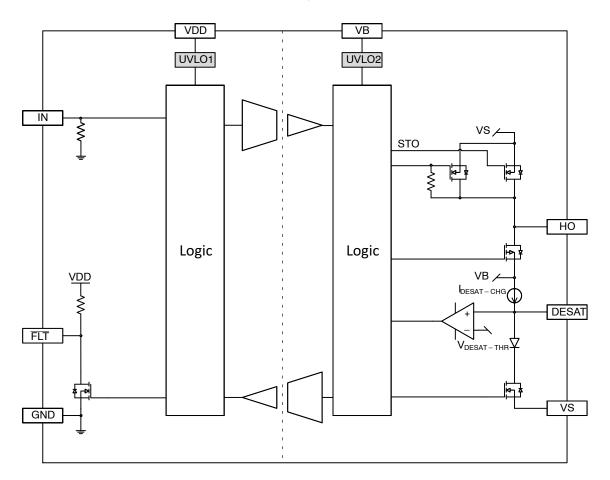


Figure 1. Simplified Block Diagram

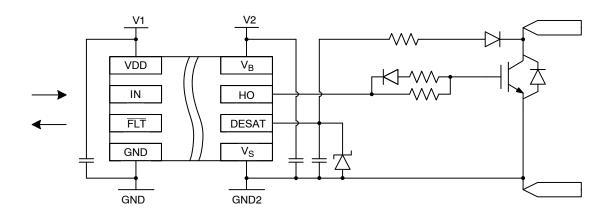


Figure 2. Simplified Application Schematics

FUNCTION DESCRIPTION

| Pin Name | No. | I/O | Description |
|-----------------|-----|-------|---|
| V _{DD} | 1 | Power | Input side power supply. A good quality bypassing capacitor is required from this pin to GND and should be placed close to the pins for best results. |
| | | | The under voltage lockout (UVLO1) circuit enables the device to operate at power on when a typical supply voltage higher than V _{UVLO1-OUT-ON} is present. Please see Figure 4 for more details. |
| IN | 2 | I | Non-inverted gate driver input. It is internally clamped to GND and has an equivalent pull-down resistor of 100 k Ω to ensure that output is low in the absence of an input signal. |
| FLT | 3 | 0 | Fault output (active low) that allows communication to the main controller that the driver has encountered a desaturation, or UVLO1, or UVLO2 condition and has deactivated the output. There is an internal 50 k Ω pull-up resistor connected to this pin. Multiple of them from different drivers can be "OR"ed together. |
| | | | FLT and HO will go high automatically after t _{MUTE} expires along with a rising edge of IN to avoid partial output pulse on HO. This is a feature called "Re-start". |
| GND | 4 | Power | Input side ground reference. |
| V _S | 5 | Power | Output side ground reference. |
| DESAT | 6 | I/O | Input for detecting the desaturation of IGBT due to a short circuit condition. An internal constant current source I _{DESAT-CHG} charging an external capacitor connected to this pin allows a programmable blanking delay every ON cycle before DESAT fault is processed, thus preventing false triggering. When the DESAT voltage goes up and reaches V _{DESAT-THR} , the output is driven low. Further, the FLT output is activated, please refer to Figure 6. FLT and HO will be kept low (including soft turn off time) at least for a period defined by t _{MUTE} . |
| НО | 7 | 0 | Driver output that provides the appropriate drive voltage and source/sink current to the IGBT/FET gate. HO is actively pulled low during start-up. |
| V _B | 8 | Power | Output side positive power supply. The operating range for this pin is from UVLO2 to its maximum allowed value. A good quality bypassing capacitor is required from this pin to $V_{\rm S}$ and should be placed close to the pins for best results. |
| | | | The under voltage lockout (UVLO2) circuit enables the device to operate at power on when a typical supply voltage higher than V _{UVLO2-OUT-ON} is present. Please see Figure 5 for more details. |

SAFETY AND INSULATION RATINGS

| Symbol | Parameter | | Value | Unit |
|-----------------------|--|--|-----------------|------------------|
| | Installation Classifications per DIN VDE 0110/1.89 | < 150 V _{RMS} | I–IV | |
| | Table T Rated Mains Voltage | < 300 V _{RMS} | I–IV | |
| | | ated Mains Voltage < 300 V _{RMS} < 300 V _{RMS} < 450 V _{RMS} < 600 V _{RMS} < 1000 V _{RMS} < 1000 V _{RMS} < 1000 V _{RMS} Degree (DIN VDE 0110/1.89) ive Tracking Index (DIN IEC 112/VDE 0303 Part 1) Dutput Test Voltage, Method b, V _{IORM} × 1.875 = V _{PR} , duction Test with t _m = 1 s, Partial Discharge < 5 pC | I–IV | |
| | | < 600 V _{RMS} | I–IV | |
| | | < 1000 V _{RMS} | I–III | |
| | Climatic Classification | | 40/100/21 | |
| | Pollution Degree (DIN VDE 0110/1.89) | | 2 | |
| CTI | Comparative Tracking Index (DIN IEC 112/VDE 0303 Part 1) | | 600 | |
| V _{PR} | Input-to-Output Test Voltage, Method b, $V_{IORM} \times 1.875 = V_{PR}$, 100% Production Test with $t_m = 1$ s, Partial Discharge < 5 pC | | 2250 | V _{PK} |
| VIORM | Maximum Repetitive Peak Voltage | | 1200 | V _{PK} |
| V _{IOWM} | Maximum Working Insulation Voltage | | 870 | V _{RMS} |
| V _{IOTM} | Highest Allowable Over Voltage | | 4200 | V _{PK} |
| E _{CR} | External Creepage | | 4.0 | mm |
| E _{CL} | External Clearance | | 4.0 | mm |
| DTI | Insulation Thickness | | 8.65 | μm |
| T _{Case} | Safety Limit Values – Maximum Values in Failure; Case Temperat | ture | 150 | °C |
| P _{S,INPUT} | Safety Limit Values – Maximum Values in Failure; Input Power | | 132 | mW |
| P _{S,OUTPUT} | Safety Limit Values – Maximum Values in Failure; Output Power | | 1128 | mW |
| R _{IO} | Insulation Resistance at TS, V _{IO} = 500 V | | 10 ⁹ | Ω |

ISOLATION CHARACTERISTICS

| Symbol | Parameter | Conditions | Value | Unit |
|------------------------------------|--------------------------------|--|------------------|------------------|
| V _{ISO,} INPUT- OUTPUT | Input-Output Isolation Voltage | T_A = 25°C, Relative Humidity < 50%, t = 1.0 minute, I_{I-O} < 30 $\mu A,$ 50 Hz (Notes 1, 2, 3) | 2500 | V _{RMS} |
| R _{ISO} | Isolation Resistance | V _{I-O} = 500 V (Note 1) | 10 ¹¹ | Ω |

 Device is considered a two-terminal device: pins 1 to 4 are shorted together and pins 5 to 8 are shorted together.
2,500 VRMS for 1-minute duration is equivalent to 3,000 VRMS for 1-second duration.
The input-output isolation voltage is a dielectric voltage rating per UL1577. It should not be regarded as an input-output continuous voltage rating. For the continuous working voltage rating, refer to equipment-level safety specification or DIN VDE V 0884-11 Safety and Insulation Ratings Table.

| Symbol | Parameter | Minimum | Maximum | Unit |
|-----------------------|---|---------|-----------------------|------|
| V _{DD} – GND | Supply Voltage, Input Side | -0.3 | 22 | V |
| $V_B - V_S$ | Supply Voltage, Output Side | -0.3 | 32 | V |
| $V_{HO} - V_S$ | Gate-driver Output Voltage | -0.3 | V _{BS} + 0.3 | V |
| I _{PK-SRC} | Gate-driver Output Sourcing Peak Current (maximum pulse width = 10 μs , maximum duty cycle = 0.2%, V_D-V_S = 15 V) | - | 7 | A |
| I _{PK-SNK} | Gate-driver Output Sinking Peak Current (maximum pulse width = 10 μs , maximum duty cycle = 0.2%, V_D-V_S = 15 V) | - | 7.5 | A |
| V _{IN} – GND | Voltage at IN, FLT | -0.3 | V _{DD} + 0.3 | V |
| I _{FLT} | Output current of FLT | - | 10 | mA |
| $V_{DESAT} - V_{S}$ | Voltage at DESAT (Note 5) | -9 | V _{BS} + 0.3 | V |
| PD | Power Dissipation (Note 6) | - | 1123 | mW |
| ESD _{HBM} | ESD Capability, Human Body Model (Note 7) | - | ±2 | kV |
| ESD _{CDM} | ESD Capability, Charged Device Model (Note 7) | - | ±2 | kV |
| MSL | Moisture Sensitivity Level | - | 1 | - |
| T _J (max) | Maximum Junction Temperature | -40 | 150 | °C |
| T _{STG} | Storage Temperature Range | -65 | 150 | °C |
| T _{SLD} | Lead Temperature Soldering Reflow, Pb-Free (Note 8) | - | 260 | °C |

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

4. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

5. The minimum value is verified by characterization with a single pulse of 1.5 mA for 300 μ s.

6. The value is estimated for ambient temperature 25°C and junction temperature 150°C, 650 mm², 1 oz copper, 2 surface layers and 2 internal power plane layers. Power dissipation is affected by the PCB design and ambient temperature.

 This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per AEC–Q100–002 (EIA/JESD22–A114). ESD Charged Device Model tested per AEC–Q100–011 (EIA/JESD22–C101).

Latchup Current Maximum Rating: ≤100 mA per JEDEC standard: JESD78, 125°C.

8. For information, please refer to our Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

THERMAL CHARACTERISTICS (Note 9, 10)

| Symbol | Parameter | Conditions | Value | Unit |
|-----------------|-------------------------------------|--|-------|------|
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Air | 100 mm ² , 1 oz Copper, 1 Surface Layer | 179 | °C/W |
| | | 100 mm ² , 1 oz Copper, 2 Surface Layers and 2 Internal Power Plane Layers | 110 | |

9. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

10. Values based on copper area of 100 mm² (or 0.16 in²) of 1 oz copper thickness and FR4 PCB substrate.

OPERATING RANGES (Note 11)

| Symbol | Parameter | Min | Max | Unit |
|--------------------------------|--------------------------------|-------|-----------------|-------|
| V _{DD} –GND | Supply Voltage, Input Side | UVLO1 | 20 | V |
| V _B -V _S | Supply Voltage, Output Side | UVLO2 | 30 | V |
| V _{IN} | Logic Input Voltage at IN | GND | V _{DD} | V |
| dV _{ISO} /dt | Common Mode Transient Immunity | 100 | - | kV/μs |
| T _A | Ambient Temperature | -40 | 125 | °C |

Functional operation above the stresses listed in the Recommended Operating Ranges is not implied. Extended exposure to stresses beyond the Recommended Operating Ranges limits may affect device reliability.

11. Refer to ELECTRICAL CHARACTERISTICS and APPLICATION INFORMATION for Safe Operating Area.

ELECTRICAL CHARACTERISTICS $V_{DD} = 5 V$, $V_{BS} = 15 V$. For typical values $T_A = 25^{\circ}C$, for min/max values, T_A is the operating ambient temperature range that applies, unless otherwise noted.

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Unit |
|----------------------------|---------------------------------|--|------|------|------|------|
| VOLTAGE SUPPL | Y | | | | | |
| V _{UVLO1-OUT-ON} | UVLO1 Output Enabled | | - | - | 3.1 | V |
| V _{UVLO1-OUT-OFF} | UVLO1 Output Disabled | | 2.4 | - | - | V |
| V _{UVLO1-HYST} | UVLO1 Hysteresis | | 0.1 | - | - | V |
| V _{UVLO2-OUT-ON} | UVLO2 Output Enabled | | 12.4 | 12.9 | 13.4 | V |
| V _{UVLO2-OUT-OFF} | UVLO2 Output Disabled | | 11.5 | 12 | 12.5 | V |
| V _{UVLO2-HYST} | UVLO2 Hysteresis | | 0.7 | 1 | - | V |
| I _{DD-0-3.3} | Input Supply Quiescent Current | $IN = Low, V_{DD} = 3.3 V, \overline{FLT} = Hig$ | - | - | 2 | mA |
| I _{DD-0-5} | | $IN = Low, V_{DD} = 5 V, \overline{FLT} = High$ | - | - | 2 | mA |
| I _{DD-0-15} | | IN = Low, V _{DD} = 15 V, FLT = High | - | - | 2 | mA |
| I _{DD-100-5} | | IN = High, V _{DD} = 5 V, FLT = High | - | - | 6 | mA |
| I _{BS-0} | Output Supply Quiescent Current | IN = Low, no load | - | - | 4 | mA |
| I _{BS-100} | | IN = High, no load | _ | - | 6 | mA |
| LOGIC INPUT AN | D OUTPUT | • | | • | - | |

| V _{IL} | Low Input Voltage (Note 12) | | | | $0.3 \times V_{\text{DD}}$ | V |
|----------------------|--|-------------------------|--------------------|----------------------|----------------------------|----|
| V _{IH} | High Input Voltage (Note 12) | | $0.7 	imes V_{DD}$ | | | V |
| V _{IN-HYST} | Input Hysteresis Voltage (Note 12) | | | $0.15 \times V_{DD}$ | | V |
| l _{IN} | Input Current | $V_{IN} = V_{DD}$ | | 50 | | μA |
| I _{FLT-L} | FLT Pull–up Current (50 kΩ pull–up resistor) | V _{FLT} = Low | - | 100 | - | μA |
| V _{FLT-L} | FLT Low Level Output Voltage | I _{FLT} = 5 mA | - | - | 0.3 | V |
| t _{MIN1} | Input Pulse Width of IN for No Response at Output | | - | - | 10 | ns |
| t _{MIN2} | Input Pulse Width of IN for Guaranteed Response at Output | | 40 | - | - | ns |

DRIVER OUTPUT

| V _{HOL1} | Output Low State | I _{SNK} = 200 mA | - | 0.1 | 0.22 | V |
|----------------------|--|---|---|-----|------|---|
| V _{HOL2} | (V _{HO} – V _S) | I_{SNK} = 1.0 A, T_A = 25°C | - | 0.4 | 1 | |
| V _{HOH1} | Output High State | I _{SRC} = 200 mA | - | 0.2 | 0.35 | V |
| V _{HOH2} | (V _B – V _{HO}) | I_{SRC} = 1.0 A, T_{A} = 25°C | - | 0.6 | 1.7 | |
| I _{PK-SNK1} | Peak Driver Current, Sink (Note 13) | | - | 7.5 | - | А |
| I _{PK-SNK2} | Peak Driver Current, Sink (Note 13) | V _{HO} = 9 V (near IGBT Miller Plateau) | - | 7 | - | А |
| I _{PK-SRC1} | Peak Driver Current, Source (Note 13) | | - | 7 | - | А |
| I _{PK-SRC2} | Peak Driver Current, Source (Note 13) | V _{HO} = 9 V (near IGBT Miller Plateau) | - | 5 | - | A |
| DESAT PROTEC | TION | | | | | |

| V _{DESAT-THR} | DESAT Threshold Voltage | | 8.4 | 9 | 9.5 | V |
|------------------------|----------------------------|-----------------------------|------|-----|------|----|
| V _{DESAT-NEG} | DESAT Negative Voltage | I _{DESAT} = 1.5 mA | - | -8 | - | V |
| I _{DESAT-CHG} | Blanking Charge Current | V _{DESAT} = 7 V | 0.45 | 0.5 | 0.55 | mA |
| I _{DESAT-DIS} | Blanking Discharge Current | | - | 50 | - | mA |

ELECTRICAL CHARACTERISTICS (continued) $V_{DD} = 5 V$, $V_{BS} = 15 V$. For typical values $T_A = 25^{\circ}C$, for min/max values, T_A is the operating ambient temperature range that applies, unless otherwise noted.

| Symbol | Parameter | Test Conditions | Min | Тур | Max | Unit |
|--------------------------|--|--|-----|------|-----|------|
| GBT SHORT CI | RCUIT CLAMPING | | | | | |
| V _{CLP-HO} | IGBT Short Circuit Clamping (V _{HO} – V _B) | $\label{eq:IN} \begin{array}{l} \text{IN}=\text{High}, \ \text{I}_{\text{HO}}=\text{500 mA}, \\ \text{t}_{\text{CLP}}=\text{10} \ \mu\text{s} \end{array}$ | - | 0.7 | 1.5 | V |
| DYNAMIC CHAR | ACTERISTICS | - | | | | |
| t _{PD-ON} | IN to HO High Propagation Delay | C_{LOAD} = 10 nF V _{IH} to 10% of HO Change for PW > 150 ns | 40 | 60 | 90 | ns |
| t _{PD-OFF} | IN to HO Low Propagation Delay | C_{LOAD} = 10 nF V _{IL} to 90% of HO Change for PW > 150 ns | 40 | 60 | 90 | ns |
| t DISTORT | Propagation Delay Distortion | $T_A = 25^{\circ}C, PW > 150 \text{ ns}$ | - | 0 | - | ns |
| | (= t _{PD-ON} – t _{PD-OFF}) | $T_A = -40^{\circ}C$ to 125°C, PW > 150 ns | -25 | - | 25 | 1 |
| ^t DISTORT_TOT | Prop Delay Distortion between Parts | PW > 150 ns | -30 | 0 | 30 | ns |
| t _{RISE} | Rise Time (see Figure 3) (Note 13) | C _{LOAD} = 1 nF, 10% to 90% of HO Change | - | 10 | - | ns |
| t _{FALL} | Fall Time (see Figure 3) (Note 13) | C _{LOAD} = 1 nF, 90% to 10% of HO Change | - | 15 | - | ns |
| t _{LEB} | DESAT Leading Edge Blanking Time (See Figure 6) | | 200 | 450 | 700 | ns |
| ^t FILTER | DESAT Threshold Filtering Time (see Figure 6) | | - | 320 | 600 | ns |
| t _{STO} | Soft Turn Off Time (see Figure 6) | C_{LOAD} = 10 nF, R_{G} = 10 Ω | 1.2 | 1.8 | 3 | μs |
| t _{FLT} | Delay after t _{FILTER} to FLT Low | | 100 | 450 | 700 | ns |
| t _{FLT1} | Delay from V <u>UVL</u> 01–OUT–OFF Triggered to FLT Low | | - | 1.5 | _ | μs |
| t _{FLT2} | Delay from t_{UVF2} to \overline{FLT} Low | | - | 2.4 | - | μs |
| t _{MUTE} | IN Mute Time after t _{FILTER} , or UVLO1, UVLO2 Triggered | | 20 | _ | - | μs |
| t _{UVR1} | Delay from V _{UVLO1-OUT-ON} Triggered to HO High | (Note 13) | - | 770 | - | ns |
| t _{UVF1} | Delay from V _{UVLO1-OUT-OFF} Triggered to HO Low | (Note 13) | _ | 1500 | _ | ns |
| t _{UVR2} | Delay from V _{UVLO2-OUT-ON} Triggered to HO High | (Note 13) | - | 1000 | - | ns |
| t _{UVF2} | Delay from V _{UVLO2-OUT-OFF} Triggered to HO Low (see Figure 5) | (Note 13) | - | 1000 | _ | ns |

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 12. Table values are valid for 3.3 V and 5 V V_{DD} , for higher V_{DD} voltages, the threshold values are maintained at the 5 V V_{DD} levels.

13. Values based on design and/or characterization.

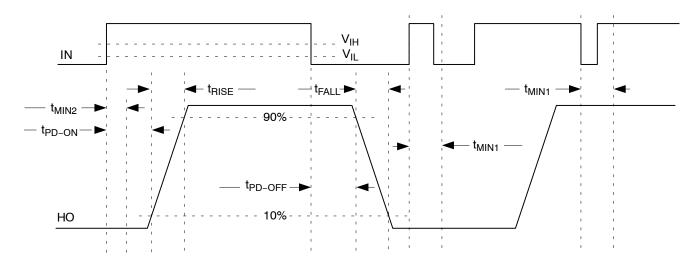


Figure 3. Propagation Delay, Rise and Fall Time

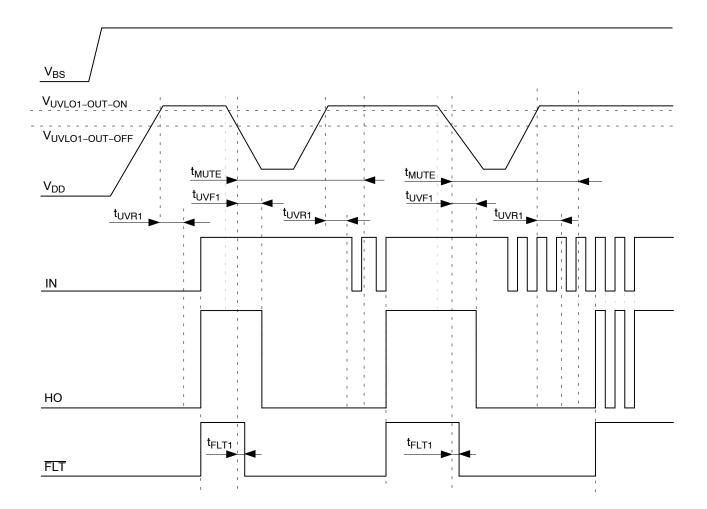


Figure 4. UVLO1 Waveform

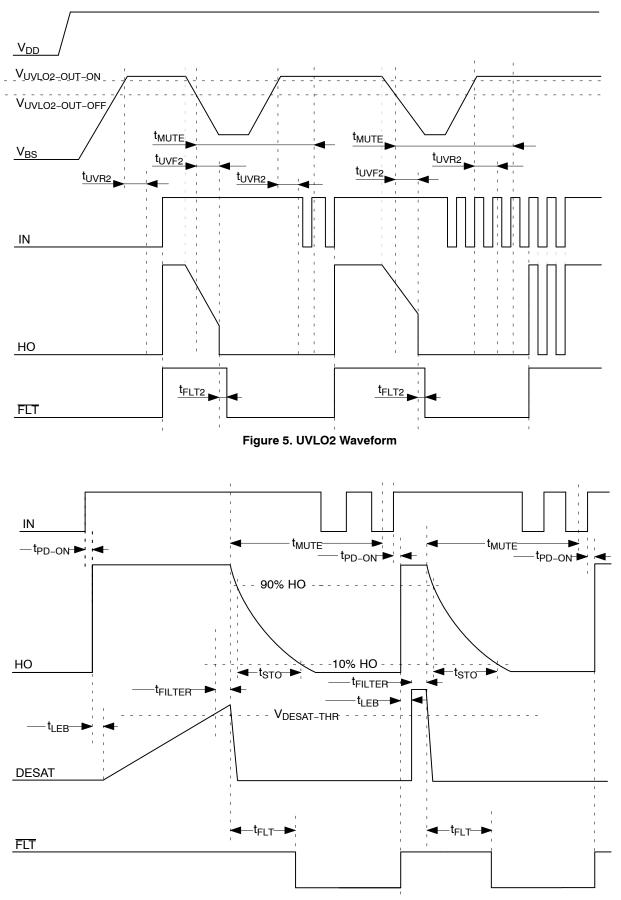


Figure 6. DESAT Response Waveform

TRUTH TABLE

| IN | UVLO1 | UVLO2 | DESAT | НО | FLT | Notes |
|----|----------|----------|---------------------------|----|-----|--|
| L | Inactive | Inactive | L | L | L | Initial condition after power up V_{DD} and V_{BS} |
| 7 | Inactive | Inactive | L | Z | 7 | Initial condition – IN First Rising edge |
| Н | Inactive | Inactive | L | Н | Н | Normal Operation – Output High |
| К | Inactive | Inactive | L | R | Н | Normal Operation – Turn off Output |
| L | Inactive | Inactive | L | L | Н | Normal Operation – Output Low |
| Х | Active | Inactive | Х | L | L | UVLO1 Activated – FLT Low (t _{FLT1}), Output Low |
| 7 | Inactive | Inactive | L | Z | 7 | FLT reset, UVLO1 conditions disappear |
| Х | Inactive | Active | Х | L | L | UVLO2 Activated – FLT Low (t _{FLT1}), Output Low |
| 7 | Inactive | Inactive | L | 7 | 7 | FLT reset, UVLO2 conditions disappear |
| Н | Inactive | Inactive | H (>t _{FILTER}) | L | L | DESAT Activated – FLT Low (t _{FLT}), Output Low |
| 7 | Inactive | Inactive | L | 7 | 7 | FLT reset, DESAT conditions disappear |

ORDERING INFORMATION

| Device | Package | Shipping [†] |
|--------------|-------------------------------|-----------------------|
| NCD57084DR2G | SOIC-8 Narrow Body, (Pb-Free) | 2500 / Tape & Reel |
| NCV57084DR2G | SOIC-8 Narrow Body, (Pb-Free) | 2500 / Tape & Reel |

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

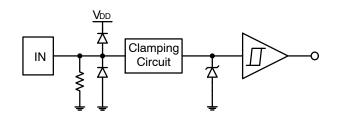
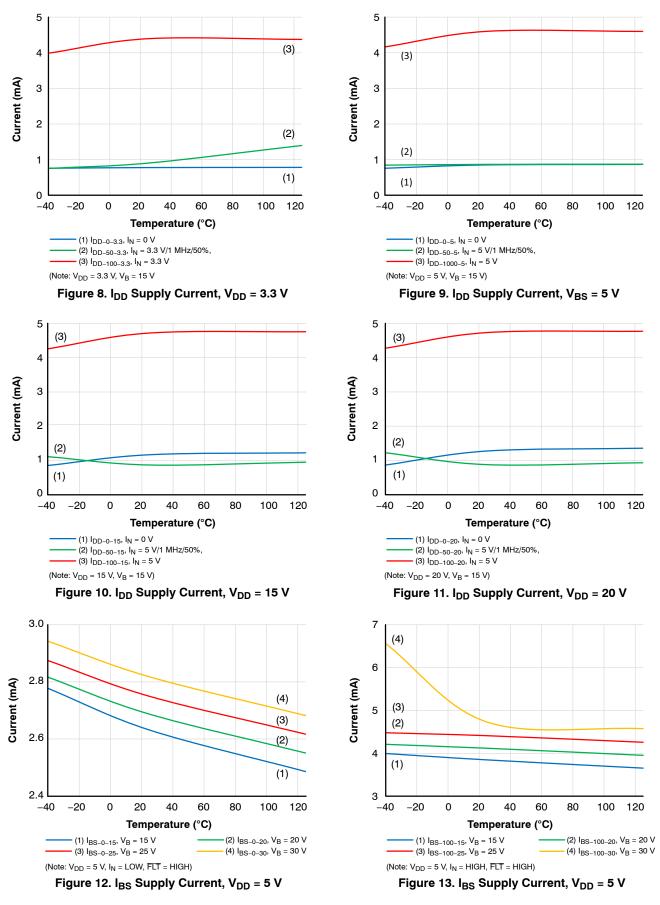
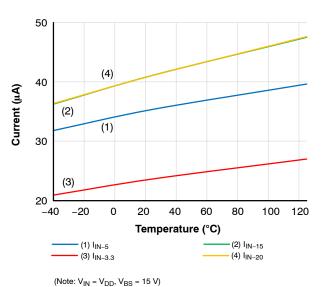
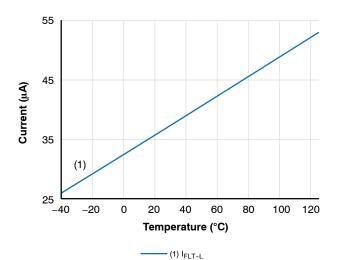


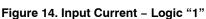
Figure 7. Input Pin Structure

TYPICAL CHARACTERISTICS









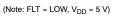
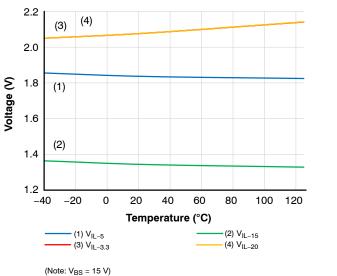
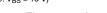
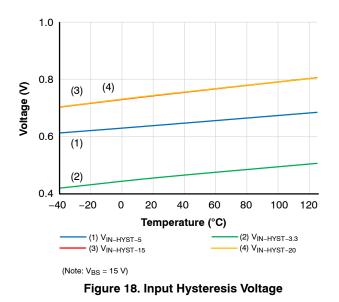


Figure 15. FLT = Pull-up Current









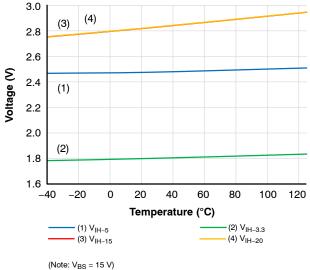
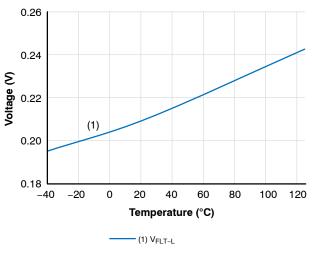
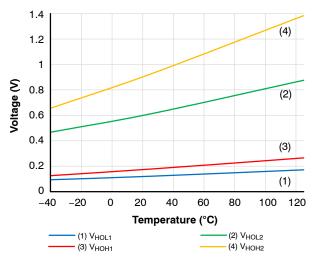


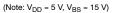
Figure 17. High Input Voltage



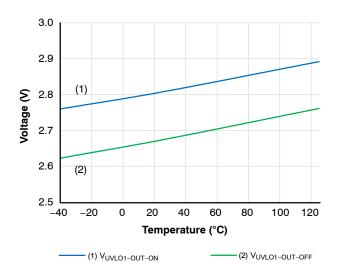
(Note: I_{FLT} = 5 mA)

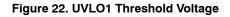
Figure 19. FLT Low Level Output Voltage

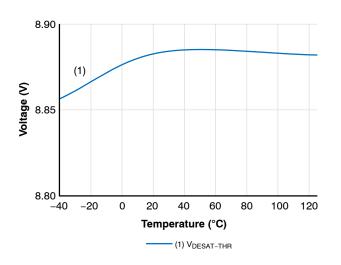




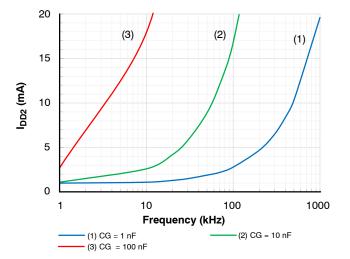




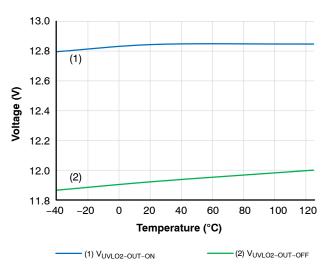


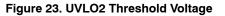












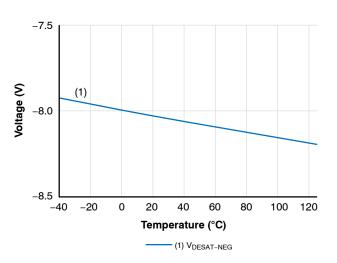
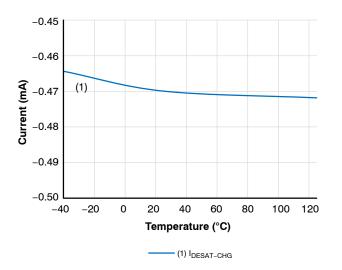


Figure 25. DESAT Negative Voltage



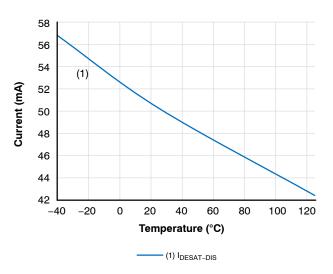


Figure 26. DESAT Blanking Charge Current

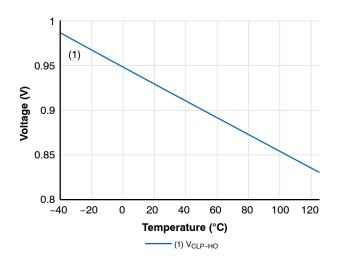


Figure 28. IGBT Short Circuit Clamping Voltage

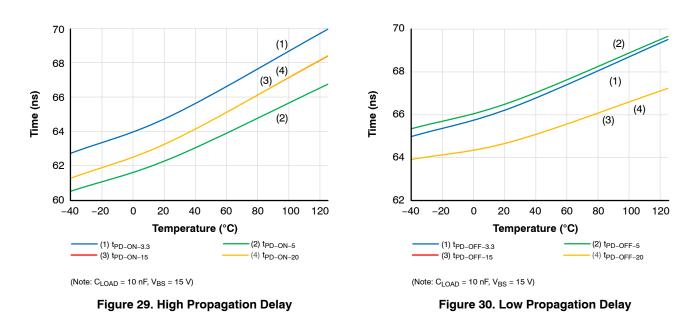
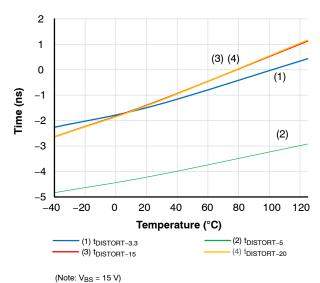
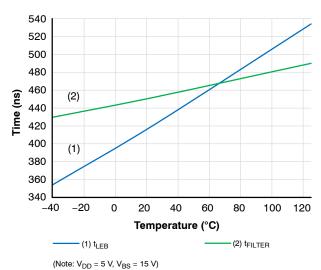


Figure 27. DESAT Blanking Discharge Current

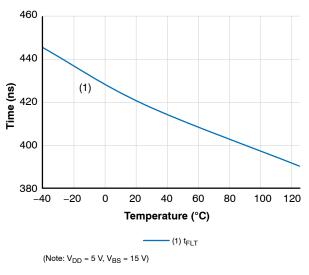




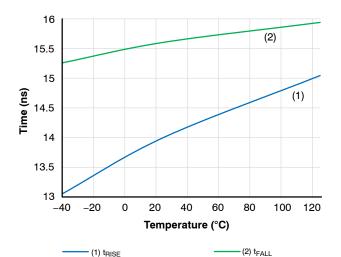






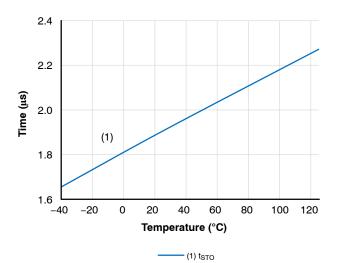






(Note: $C_{LOAD} = 1 \text{ nF}, V_{BS} = 15 \text{ V}$)





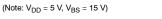


Figure 34. Soft Turn Off Time

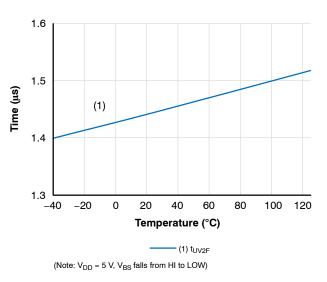


Figure 36. UVLO2 Fall Delay

Under Voltage Lockout (UVLO)

UVLO ensures correct switching of IGBT connected to the driver output.

- The IGBT is turned-off and the output is disabled, if the supply V_{DD} drops below V_{UVLO1-OUT-OFF} or V_{BS} drops below V_{UVLO2-OUT-OFF}.
- The driver output does not follow the input signal on V_{IN} until the V_{DD} / V_{BS} rises above the $V_{UVLOX-OUT-ON}$ and the input signal rising edge is applied to the V_{IN} .

With high loading gate capacitances over 10 nF it is important to follow the decoupling capacitor routing guidelines as shown on Figure 37. The decoupling capacitor value should be at least 10 μ F. Also gate resistor of minimal value of 2 Ω has to be used in order to avoid interference of the high di/dt with internal circuitry (e.g. UVLO2).

After the power-on of the driver there has to be a rising edge applied to the IN in order for the output to start following the inputs. This serves as a protection against producing partial pulses at the output if the V_{DD} or V_B is applied in the middle of the input PWM pulse.

Power Supply (V_{DD}, V_{BS})

NCx57084 is designed to support unipolar power supply.

For reliable high output current the suitable external power capacitors required. Parallel combination of 100 nF + 4,7 μ F ceramic capacitors is optimal for a wide range of applications using IGBT. For reliable driving IGBT modules (containing several parallel IGBT's) a higher capacity required (typically 100 nF + 10 μ F). Capacitors should be as close as possible to the driver's power pins.

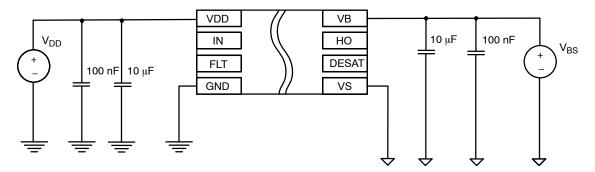


Figure 37. Power Supply

Desaturation Protection (DESAT)

Desaturation protection ensures the protection of IGBT at short circuit. When the V_{CESAT} voltage goes up and reaches the set limit, the output is driven low and \overline{FLT} output is activated. Blanking time can be set by internal current source and an external capacitor. To avoid false DESAT triggering and minimize blanking time, fast switching diodes with low internal capacitance are recommended. All DESAT protective diodes internal capacitances builds voltage divider with the blanking capacitor.

<u>Warning</u>: Both external protective diodes are recommended for the protection against voltage spikes caused by IGBT transients passing through parasitic capacitances.

$$t_{BLANK} = C_{BLANK} \cdot \frac{V_{DESAT-THR}}{I_{DESAT-CHG}}$$
$$V_{DESAT-THR} > R_{S-DESAT} \cdot I_{DESAT-CHG} + V_{F HV \, diode} + V_{CESAT_IGBT}$$

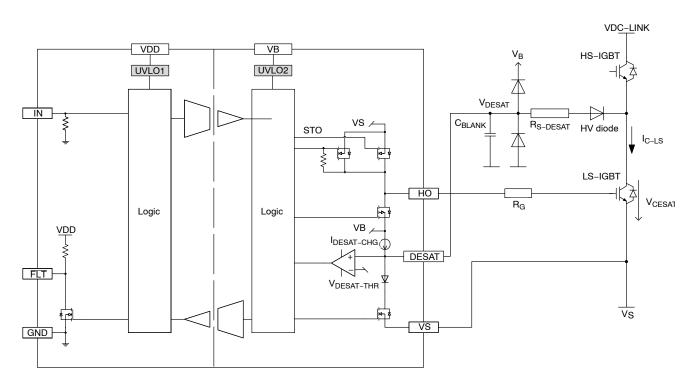
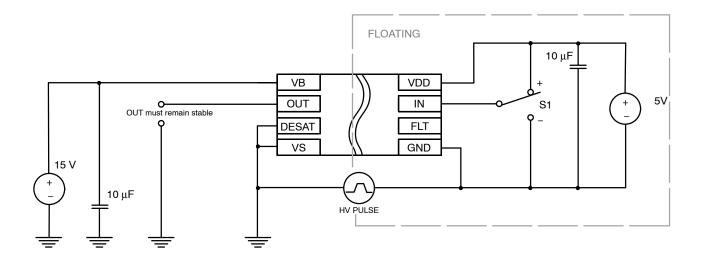


Figure 38. DESAT Circuit Parameters Specification



(Test Conditions: HV Pulse ± 1500 V, dV/dt = 1–100 V/ns, V_{DD} = 5 V, V_{BS} = 15 V)

Figure 39. CMTI Test Setup

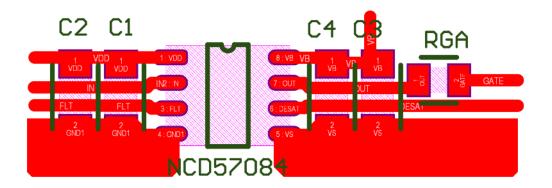
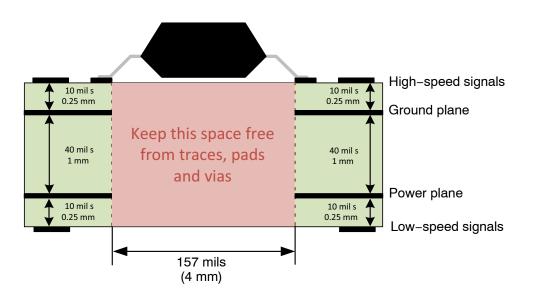


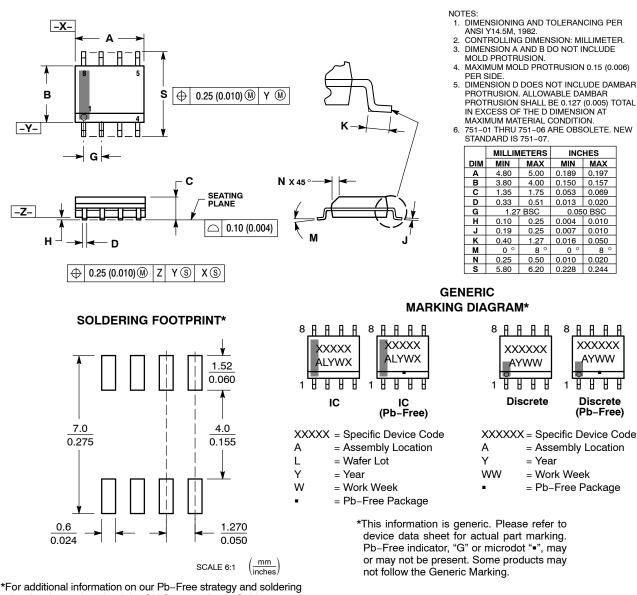
Figure 40. Recommended Layout





PACKAGE DIMENSIONS

SOIC-8 NB CASE 751-07 ISSUE AK



*For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

STYLES ON PAGE 2

SOIC-8 NB

CASE 751-07

ISSUE AK

STYLE 1: PIN 1. EMITTER COLLECTOR 2. 3. COLLECTOR 4. EMITTER 5. EMITTER BASE 6. 7 BASE 8. EMITTER STYLE 5: PIN 1. DRAIN 2. DRAIN 3. DRAIN DRAIN 4. GATE 5. 6. GATE SOURCE 7. 8. SOURCE STYLE 9: PIN 1. EMITTER, COMMON 2. COLLECTOR, DIE #1 COLLECTOR. DIE #2 З. EMITTER, COMMON 4. 5. EMITTER, COMMON 6 BASE. DIE #2 BASE, DIE #1 7. 8. EMITTER, COMMON STYLE 13: PIN 1. N.C. 2. SOURCE 3 GATE 4. 5. DRAIN 6. DRAIN DRAIN 7. DRAIN 8. STYLE 17: PIN 1. VCC 2. V2OUT V10UT З. TXE 4. 5. RXE 6. VFF 7. GND 8. ACC STYLE 21: PIN 1. CATHODE 1 2. CATHODE 2 3 CATHODE 3 CATHODE 4 4. 5. CATHODE 5 6. COMMON ANODE COMMON ANODE 7. 8. CATHODE 6 STYLE 25: PIN 1. VIN 2 N/C REXT З. 4. GND 5. IOUT IOUT 6. IOUT 7. 8. IOUT STYLE 29: BASE, DIE #1 PIN 1. 2 EMITTER, #1 BASE. #2 З. EMITTER, #2 4. 5 COLLECTOR, #2 COLLECTOR, #2 6. 7. COLLECTOR, #1 8 COLLECTOR, #1

STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 COLLECTOR, #2 3. 4 COLLECTOR, #2 BASE, #2 5. EMITTER, #2 6. 7 BASE #1 EMITTER, #1 8. STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN SOURCE 4. SOURCE 5. 6. GATE GATE 7. 8. SOURCE STYLE 10: GROUND PIN 1. BIAS 1 OUTPUT 2. З. GROUND 4. 5. GROUND 6. BIAS 2 INPUT 7. 8. GROUND STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3 P-SOURCE P-GATE 4. P-DRAIN 5. 6. P-DRAIN N-DRAIN 7. N-DRAIN 8. STYLE 18: PIN 1. ANODE ANODE 2. SOURCE 3. GATE 4. 5. DRAIN 6 DRAIN CATHODE 7. CATHODE 8. STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3 COMMON CATHODE/VCC 4. I/O LINE 3 COMMON ANODE/GND 5. 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND STYLE 26: PIN 1. GND 2 dv/dt З. ENABLE 4. ILIMIT 5. SOURCE SOURCE 6. SOURCE 7. 8. VCC STYLE 30: DRAIN 1 PIN 1. DRAIN 1 2 GATE 2 З. SOURCE 2 4. 5. SOURCE 1/DRAIN 2 SOURCE 1/DRAIN 2

6.

7.

8 GATE 1

SOURCE 1/DRAIN 2

STYLE 3: PIN 1. DRAIN, DIE #1 DRAIN, #1 2. DRAIN, #2 З. 4. DRAIN, #2 GATE, #2 5. SOURCE, #2 6. 7 GATE #1 8. SOURCE, #1 STYLE 7: PIN 1. INPUT 2. EXTERNAL BYPASS З. THIRD STAGE SOURCE GROUND 4. 5. DRAIN 6. GATE 3 SECOND STAGE Vd 7. 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 GATE 1 SOURCE 2 2. 3. GATE 2 4. 5. DRAIN 2 6. DRAIN 2 DRAIN 1 7. 8. DRAIN 1 STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3 ANODE 1 ANODE 1 4. 5. CATHODE, COMMON 6. CATHODE, COMMON CATHODE, COMMON 7. CATHODE, COMMON 8. STYLE 19: PIN 1. SOURCE 1 GATE 1 SOURCE 2 2. 3. GATE 2 4. 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. **MIRROR 1** STYLE 23: PIN 1. LINE 1 IN COMMON ANODE/GND COMMON ANODE/GND 2. 3 LINE 2 IN 4. LINE 2 OUT 5. COMMON ANODE/GND COMMON ANODE/GND 6. 7. 8. LINE 1 OUT STYLE 27: PIN 1. ILIMIT 2 OVI 0 З. UVLO 4. INPUT+ 5. 6. SOURCE SOURCE SOURCE 7. 8 DRAIN

DATE 16 FEB 2011

STYLE 4: PIN 1. 2. ANODE ANODE ANODE З. 4. ANODE ANODE 5. 6. ANODE 7 ANODE COMMON CATHODE 8. STYLE 8: PIN 1. COLLECTOR, DIE #1 2. BASE, #1 З. BASE #2 COLLECTOR, #2 4. COLLECTOR, #2 5. 6. EMITTER, #2 EMITTER, #1 7. 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE SOURCE 2. 3. GATE 4. 5. DRAIN 6. DRAIN DRAIN 7. 8. DRAIN STYLE 16 EMITTER, DIE #1 PIN 1. 2. BASE, DIE #1 EMITTER DIE #2 3 BASE, DIE #2 4. 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 COLLECTOR, DIE #1 7. COLLECTOR, DIE #1 8. STYLE 20: PIN 1. SOURCE (N) GATE (N) SOURCE (P) 2. 3. 4. GATE (P) 5. DRAIN 6. DRAIN DRAIN 7. 8. DRAIN STYLE 24: PIN 1. BASE EMITTER 2. 3 COLLECTOR/ANODE COLLECTOR/ANODE 4. 5. CATHODE 6. CATHODE COLLECTOR/ANODE 7. 8. COLLECTOR/ANODE STYLE 28: 11. SW_TO_GND 2. DASIC OFF PIN 1. DASIC_SW_DET З. 4. GND 5. 6. V MON VBULK 7. VBULK 8 VIN

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